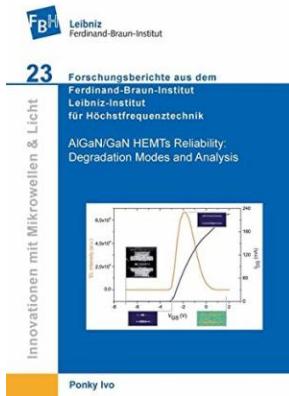


[Download PDF](#)

ALGAN/GAN HEMTS RELIABILITY



Cuvillier Verlag Okt 2012, 2012. Taschenbuch. Book Condition: Neu. 211x147x10 mm. Neuware - AlGaN/GaN HEMTs reliability and stability issues were investigated in dependence on epitaxial design and process modification. DC-Step-Stress-Tests have been performed on wafers as a fast device robustness screening method. As a criterion of robustness they deliver a critical source-drain voltage for the onset of degradation. Several degradation modes were observed which depend on epi design, epi quality and process technology. Electrical and optical characterizations together with electric...

[Download PDF AlGaN/GaN HEMTs Reliability](#)

- Authored by Ponky Ivo
- Released at 2012



Filesize: 7.97 MB

Reviews

Unquestionably, this is actually the greatest function by any author. I was able to comprehended every little thing using this created e ebook. Its been printed in an remarkably straightforward way which is merely following i finished reading this ebook in which in fact altered me, alter the way i think.

-- **Arianna Witting**

An exceptional book as well as the font used was exciting to read. It is actually rally intriguing throgh reading time. You will not sense monotony at anytime of the time (that's what catalogues are for about when you ask me).

-- **Crystel Hagenes**

This created pdf is wonderful. It is writer in easy words and never difficult to understand. You wont really feel monotony at anytime of your own time (that's what catalogs are for relating to if you request me).

-- **Mr. Kade Gibson**